

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1065	(702/57-59).CCLS.	US-PGPUB; USPAT	OR	OFF	2007/01/11 12:36
L2	937	(702/81-84).CCLS.	US-PGPUB; USPAT	OR	OFF	2007/01/11 12:38
L3	867	(702/89,108).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/01/11 12:39
L4	1020	(702/117).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/01/11 12:41
L5	595	(702/118,119).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/01/11 12:43
L6	743	(702/120,121,123,125).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/01/11 12:45
L7	1315	(324/73.1).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2007/01/11 12:46
L8	268	(324/500,537,754,765).ccls. and parametric adj test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:47
L9	273	(324/500,537,754,765).ccls. and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:48
L10	57	(438/14,16,17).ccls. and parametric adj test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:49
L11	98	(438/14,16,17).ccls. and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:49
L12	0	(parametric and (test testing tested)).ti. and (load with wafer) same (automated or automatic\$) and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:50
L13	6	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:51
L14	1	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with (controller controlling) and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:53

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L15	0	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:54
L16	0	parametric adj test\$3 and synchroniz\$3 with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:55
L17	0	parametric adj test\$3 and synchronization with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:55
L18	0	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ\$3 near (data instrumentation instrument) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:56
L19	0	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ\$3 near file and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:56
L20	0	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same load near test and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:56
L21	0	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same initializ\$3 near (data instrumentation instrument) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:56
L22	0	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same initializ\$3 near file	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:57
L23	0	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same load near test and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:57
L24	0	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ\$3 near memory	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:57
L25	0	parametric adj test\$3 and state adj oscillator and @pd>"20060119"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:57
L26	0	state adj oscillator same fault-tolerant same test\$3 and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:57
L27	0	state adj oscillator same fault-tolerant and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:58

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L28	0	state adj oscillator same test\$3 and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:58
L29	0	state adj oscillator same state near module and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:58
L30	0	state adj oscillator same state near object	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:58
L31	0	state adj oscillator same control adj state and @pd>"20060119"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:58
L32	0	state adj oscillator same superstate and @pd>"20060119"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:59
L33	2	parametric adj test\$3 and (control controlling) adj state and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:59
L34	0	(wafer adj electrical adj (test testing)) with (move moving movement) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 12:59
L35	1	(semiconductor wafer) and (move moving movement prober alignment) with (simultaneous\$2 concurrent\$2) with (initialize initialized initialization) and @pd>"20060524"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 13:00
L36	0	parametric adj test\$3 and concurrent adj operation and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 13:00
L37	0	parametric adj test\$3 and simultaneous adj operation	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 13:01
L38	0	alignment with initialization with (concurrent\$2 simultaneous\$2) and @pd>"20061024"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2007/01/11 13:01
L39	0	(semiconductor and parametric and test and control and concurrent).clm.	US-PGPUB	OR	ON	2007/01/11 13:01